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SiO2 Etch using ICP2 with O2

Recipe (#104): 0.5Pa, 50/500W, CHF3/CF4/O2=35/5/10 sccm, time=3.5 min (210 sec)

1) Run#01 (10-5-2018)

Etch rate=95.2 nm/min, Etch Selectivity (SiO2/PR) =0.74, Averaged Sidewall Angle=77.9°.

Figure 1 (a), (b), and (c) SiO2 etch profile; (d) PR etch-mask profile.



